OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

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10589137 - GAU: 2825 Sheet 1 of 1

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2825

ATTY, DOCKET NO.

71247-0064

08/07/2008

Chouki AKTOUF

APPLICANT

			U.S. PATEN	T DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME		CLASS		SUB- CLAS		FILING DATE		
	1.	2003/0023941	01/30/2003	WANG et al.								
	2.	6,256,770	07/03/2001	PIERCE et al.								
			FOREIGN PAT	ENT DOCUMENT	rs							
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		OTHER REFERE	NCES (Including	Author, Title, Date,	Pert	inent P	aces,	Etc.)				
	3.	Y. HUANG et al., "On RTL Scan Design", ITC International Test Conference, Baltimore, Maryland, October 30-November 1, 2001, IEEE, US, pgs. 728-737										
	4.	S. C. AKTOUF et al., "Inserting Scan at the Behavioral Level", IEEE Design & Test of Computers, vol. 17, no. 3, July 2000, pgs. 34-42										
EXAMINER /Brandon Bowers/			DATE CONSIDERED 09/29/2010									
*EXAMINE	cit	tial if reference considered ation if not in conformance plicant.									1	

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH, /BB/